## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | HAYBALL ET AL. | Examiner | Art Unit | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,578,066 B1	06-2003	Logan et al.	718/105
*	В	US-6,092,178 A	07-2000	Jindal et al.	712/27
*	С	US-6,233,618 B1	05-2001	Shannon, Steven	709/229
*	D	US-6,493,765 B1	12-2002	Cunningham et al.	709/245
*	Е	US-6,446,048 B1	09-2002	Wells et al.	705/35
*	F	US-6,449,657 B2	09-2002	Stanbach et al.	709/245
*	G	US-6,480,508 B1	11-2002	Mwikalo et al.	370/475
*	Н	US-6,381,651 B1	04-2002	Nishio et al.	709/245
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Z					
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	Р		<u> </u>			
	σ					
	R		<u> </u>			
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	
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